

Application/Control No.	Applicant(s)/Patent under Reexamination
10/555,536	BOUAN, BRUNO
Examiner	Art Unit
Christopher Boswell	3676

SEARCHED					
Class	Subclass	Date	Examiner		
70	57, 57.1, 58, 63	5/22/2007	СВ		
206	1.5, 307	5/22/2007	СВ		
	308.1				
	308.2				
	387.1				
	387.11				

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NO (INCLUDING SEARCI	OTES H STRATEGY	')
	DATE	EXMR
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